

## Technical Program of TestForum 2015

### Nordic Test Forum (NTF) Annual Assembly, November 23<sup>rd</sup> 2015

The NTF organization holds an annual general assembly a day before the TestForum conference. This year it will be held on **November 23<sup>rd</sup> at 20:00**. The agenda and motions will be dispatched to the members in a separate mailing.

### Tuesday, November 24<sup>th</sup>, 2015

Time	Titles	Speakers or additional info
08:30-08:50	Registration	
<b>08:50-09:00</b>	<b>Welcome / Introduction</b>	Knut Båtstøløkken
<b>09:00-10:00</b>	<b>Key Note Session</b>	<i>Chairman: Knut Båtstøløkken</i>
09:00-10:00	Driving profitability and customer success through Operational Excellence	Israel Losada Salvador, Kitron ASA
<b>10:00-10:30</b>	<b>Exhibitor Forum: short presentations</b>	<i>Chairman: Mick Austin</i>
10:30-11:00	Coffee Break / Exhibition	
<b>11:00-12:30</b>	<b>Session 1: JTAG based test</b>	<i>Chairman: Lars Kongsted-Jensen</i>
11:00-11:30	Automated test of High Speed interfaces with programmable BER	Jan Heiber, Goepel
11:30-12:00	IEEE 1687 An Introduction	Martin Keim, Mentor Graphics
12:00-12:30	Mixed-signal boundary-scan in practice	Marcel Swinnen, tpb electronics
12:30-13:30	Lunch	
<b>13:30-15:00</b>	<b>Session 2: Test Strategies and Test Quality</b>	<i>Chairman: Stig-Gunnar Jensen</i>
13:30-14:00	Functional Test – Test strategy of the future?	Lothar Diez, Spea
14:00-14:30	Big Data Solution for test	Vidar Grønås, Virinco
14:30-15:00	Out Sourced Test - Customer view	Mikko Karjalainen, Palodex
15:00-15:30	Coffee Break / Exhibition	
<b>15:30-16:30</b>	<b>Session 3: Fixturing and test interfaces</b>	<i>Chairman: Bjørn B. Larsen</i>
15:30-16:00	Benefits of eliminating cables from ATE systems	Gary Clayton, MAC-Panel
16:00-16:30	PCB design from a mechanical point of view	Per Milborg Pedersen, Mekan
<b>16:30-17:00</b>	<b>News from conferences</b>	<i>Chairman: Artur Jutman</i>
17:00-17:30	Fruit & Refreshments / Exhibition	
<b>17:30-19:00</b>	<b>Panel debate: "Is simulation removing the need for physical test?"</b>	<i>Panel moderator: Birger Schneider</i>
<b>19:30</b>	<b>Dinner</b>	

## Wednesday, November 25<sup>th</sup>, 2015

Time	Titles	Speakers or additional info
<b>09:00-10:00</b>	<b>Session 4: Invited speaker</b>	<i>Chairman: Magnus Rönnqvist</i>
09:00-10:00	The Impact of IOT on the Network and its Implication to Test	Bill Eklow, Cisco Systems
<b>10:00-11:00</b>	<b>Session 5: Quality aspects</b>	<i>Chairman: Magnus Rönnqvist</i>
10:00-10:30	Addressing No Failure Found in Board Test by Modeling and Embedded Instrumentation	Artur Jutman, Testonica Lab
10:30-11:00	High Voltage and electronic drivers	Birger Schneider, Delta
11:00-11:30	Coffee Break / Exhibition	
<b>11:30-13:00</b>	<b>Session 6: Functional test</b>	<i>Chairman: Raimedas Sodaitis</i>
11:30-12:00	The Power of Measurement IP Through the Test Lifecycle	Robert Hood, Keysight Technologies.
12:00-12:30	EMI debugging with Tektronix Mixed Domain Oscilloscope	Derek MacLachlan, Tektronix
12:30-13:00	Wheeler Analysis – A powerful alternative to a traditional Gage R&R	Mattis Ericsson, AddQ Consulting
13:00-14:00	Lunch	
<b>14:00-15:00</b>	<b>Session 7: Automatic inspection and structural test</b>	<i>Chairman: Erik Larsson</i>
14:00-14:30	Contactless testing	Abdelghani Renbi, Luleå University of Technology
14:30-15:00	Building, modular, scalable, flexible and above all reliable ATE's that last	Peter van Oostrom, 6TL
15:00-15:15	Closing Session: TestForum concluding remarks	<i>Knut Båtstøløkken Kitron</i>

## Exhibition

As usually, a mini exhibition will take place in frames of TestForum event where vendors are welcome to present their tools and methodologies related to production test. Exhibitors can make arrangements with NTF about exhibition space. If nothing special has been agreed, a table of about 60x120 cm<sup>2</sup>, as well as space for posters or similar material will be provided. Every exhibitor will be given 7-8-minute slot in the program for a brief introduction.